



Non-Contact Sheet Resistance Mapper

DATA SHEET - EddyCus[®] TF map 2525 series

HIGHLIGHTS

- Contact-free & real-time
- Accurate high resolution mapping of sheet resistance for low and highly conductive thin films (Ohm/sq)
- Layer thickness mapping of metal films (nm)
- Layer and substrate thickness monitoring (μm)
- Sheet resistance mapping of encapsulated layers
- Multiple possibilities of analyzing the mapping by an easy-to-handle software

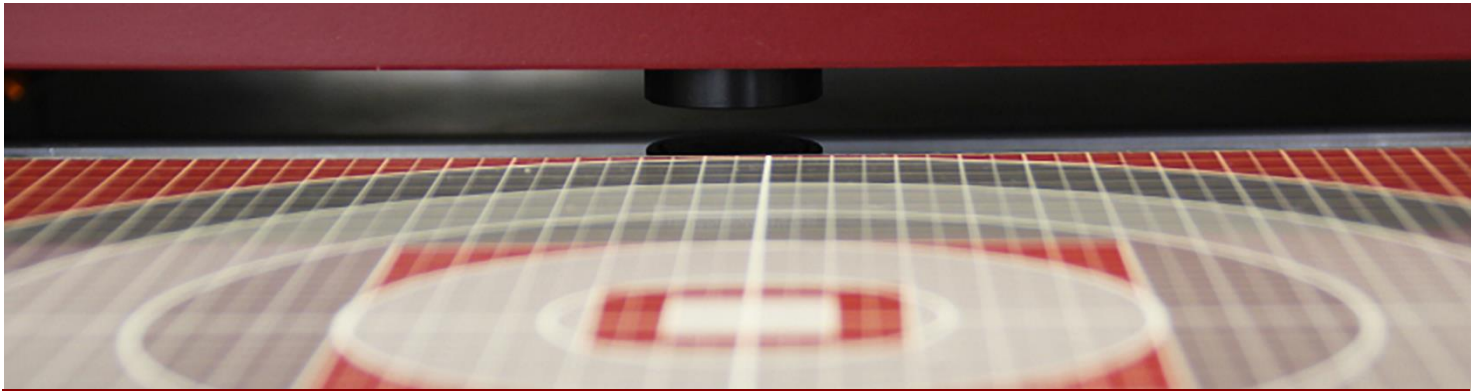
APPLICATIONS

- > Architectural glass (LowE)
- > Touch screens & flat monitors
- > OLED & LED applications
- > Smart-glass applications
- > Transparent antistatic foils
- > Photovoltaics
- > Semiconductors
- > De-icing & heating applications
- > Batteries & fuel cells
- > Packaging materials



DATA SHEET

EddyCus® TF map 2525 series – Sheet Resistance Mapping



EddyCus® TF map 2525SR series

Measurement technology	Non-contact eddy current sensor
Substrates	e.g. foil, glass, wafer
Max. scanning area	10 inch / 254 x 254 mm (larger on request)
Edge effect correction / exclusion	2 mm edge exclusion for standard sizes
Max. sample thickness/ sensor gap	2 / 5 / 10 / 25 mm (defined by the thickest sample/ application)
Sheet resistance range and accuracy	0.0001 – 10 Ohm/sq < 2% accuracy 10 – 100 Ohm/sq < 3% accuracy 100 – 1,000 Ohm/sq < 5% accuracy
Thickness mapping of metal films (e.g. Aluminum, Copper)	2 nm – 2 mm (in accordance with sheet resistance)
Scanning pitch	1 / 2 / 5 / 10 mm (other on request)
Measurement points per time (quadratic shape)	10.000 measurement points in 5 minutes 1.000.000 measurement points in 30 minutes
Scanning time	4 inch / 200 x 200 mm in 0.5 to 5 minutes (1 – 10 mm pitch) 8 inch / 200 x 200 mm in 1.5 to 15 minutes (1 – 10 mm pitch)
Device dimension (w/h/d) / Weight	23.6 x 9.05 x 31.5 inch / 600 x 230 x 800 mm / 27 kg
Available features	Metal thickness imaging Anisotropy sheet resistance sensor Optical transmission sensors at 632 nm wavelength

SOFTWARE & HANDLING – Sheet Resistance Analyzer 2.0

